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Application/Control No.	Applicant(s)/Patent under Reexamination
10/696,549	SCHNEIDER, LUKE V.
Examiner	Art Unit
Kiet T. Nguyen	2881

			
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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH S	STRATEGY)
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